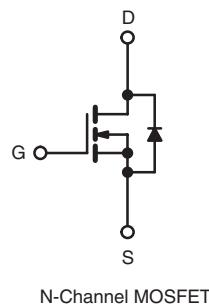
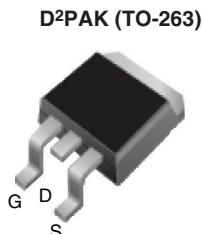


Power MOSFET

PRODUCT SUMMARY		
V _{DS} (V)	100	
R _{DS(on)} (Ω)	V _{GS} = 5 V	0.27
Q _g (Max.) (nC)		12
Q _{gs} (nC)		3.0
Q _{gd} (nC)		7.1
Configuration	Single	



FEATURES

- Surface Mount
- Available in Tape and Reel
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- R_{DS(on)} Specified at V_{GS} = 4 V and 5 V
- 175°C Operating Temperature

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The D²PAK (TO-263) is a surface mount power package capable of accommodating die size up to HEX-4. It provides the highest power capability and the lowest possible on-resistance in any existing surface mount package. The D²PAK (TO-263) is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0 W in a typical surface mount application.

ORDERING INFORMATION

Package	D ² PAK (TO-263)
SnPb	IRL520S
	SiHL520S

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	100	V
Gate-Source Voltage	V _{GS}	± 10	
Continuous Drain Current	I _D	9.2	A
		6.5	
Pulsed Drain Current ^a	I _{DM}	36	W/°C
Linear Derating Factor		0.40	
Linear Derating Factor (PCB Mount) ^e		0.025	
Single Pulse Avalanche Energy ^b	E _{AS}	170	mJ
Avalanche Current ^a	I _{AR}	9.2	A
Repetitive Avalanche Energy ^a	E _{AR}	6.0	mJ
Maximum Power Dissipation	P _D	60	W
Maximum Power Dissipation (PCB Mount) ^e		3.7	
Peak Diode Recovery dV/dt ^c	dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- V_{DD} = 25 V, starting T_J = 25 °C, L = 3.0 mH, R_G = 25 Ω, I_{AS} = 9.2 A (see fig. 12).
- I_{SD} ≤ 9.2 A, dI/dt ≤ 110 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.
- 1.6 mm from case.
- When mounted on 1" square PCB (FR-4 or G-10 material).

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	$^{\circ}\text{C}/\text{W}$
Maximum Junction-to-Ambient (PCB Mount) ^a	R_{thJA}	-	40	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	2.5	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS $T_J = 25 \text{ }^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		100	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$, $I_D = 1 \text{ mA}$		-	0.12	-	$\text{V}/^{\circ}\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		1.0	-	2.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 10 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 80 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150 \text{ }^{\circ}\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 5 \text{ V}$	$I_D = 5.5 \text{ A}^b$	-	-	0.27	Ω	
		$V_{GS} = 4 \text{ V}$	$I_D = 4.6 \text{ A}^b$	-	-	0.38	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 5.5 \text{ A}^b$		3.2	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	490	-	pF	
Output Capacitance	C_{oss}			-	150	-		
Reverse Transfer Capacitance	C_{rss}			-	30	-		
Total Gate Charge	Q_g	$V_{GS} = 5 \text{ V}$	$I_D = 9.2 \text{ A}$, $V_{DS} = 80 \text{ V}$, see fig. 6 and 13 ^b	-	-	12	nC	
Gate-Source Charge	Q_{gs}			-	-	3.0		
Gate-Drain Charge	Q_{gd}			-	-	7.1		
Turn-On Delay Time	$t_{d(on)}$			-	9.8	-		
Rise Time	t_r	$V_{DD} = 50 \text{ V}$, $I_D = 9.2 \text{ A}$, $R_G = 9 \Omega$, $R_D = 5.2 \Omega$, see fig. 10 ^b		-	64	-	ns	
Turn-Off Delay Time	$t_{d(off)}$			-	21	-		
Fall Time	t_f			-	27	-		
Dynamic								
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	L_S			-	7.5	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	9.2	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	36		
Body Diode Voltage	V_{SD}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_S = 9.2 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	2.5	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25 \text{ }^{\circ}\text{C}$, $I_F = 9.2 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	130	190	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.83	1.0	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2 \%$.

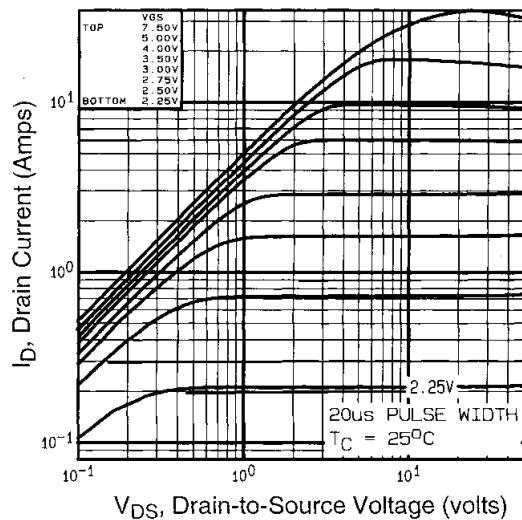
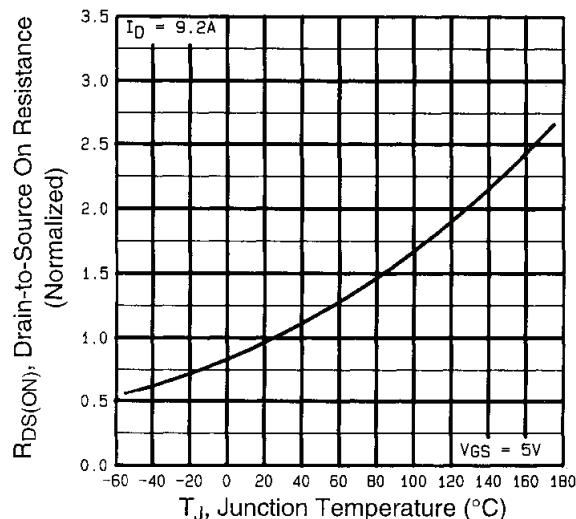
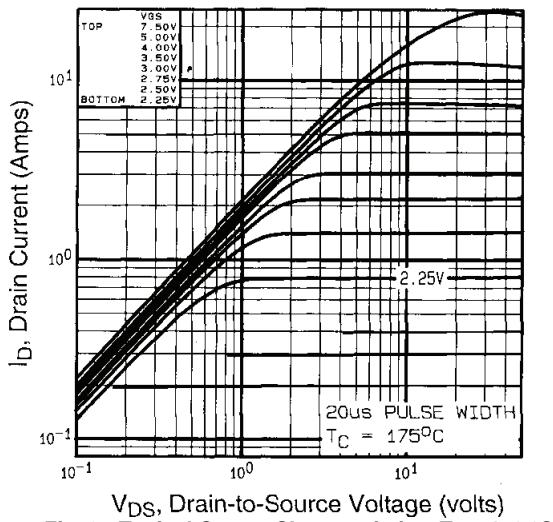
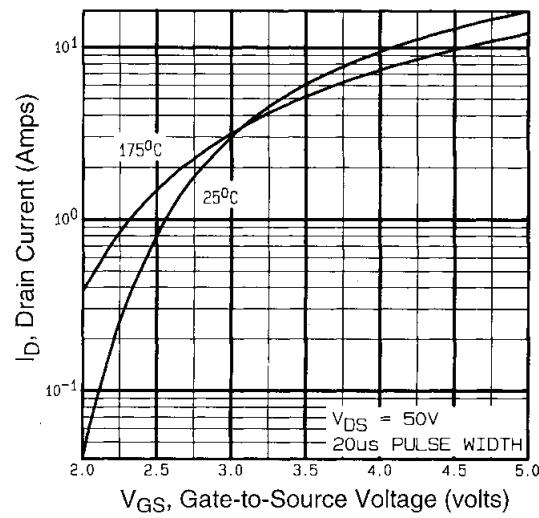
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


Fig. 1 - Typical Output Characteristics, $T_c = 25\text{ }^{\circ}\text{C}$



IRL520S, SiHL520S

Vishay Siliconix

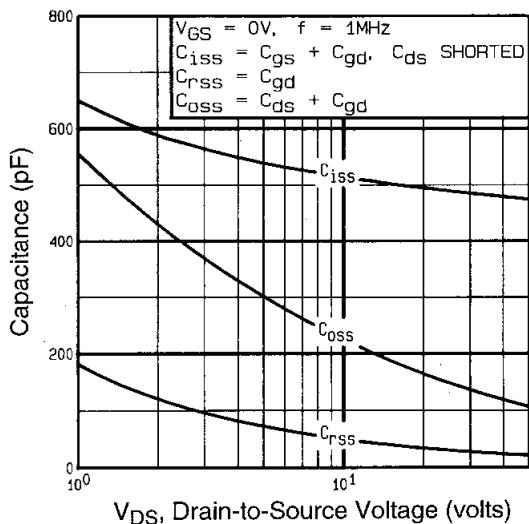


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

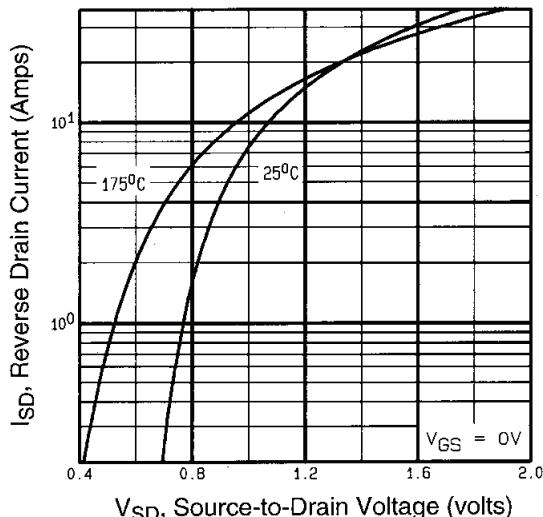


Fig. 7 - Typical Source-Drain Diode Forward Voltage

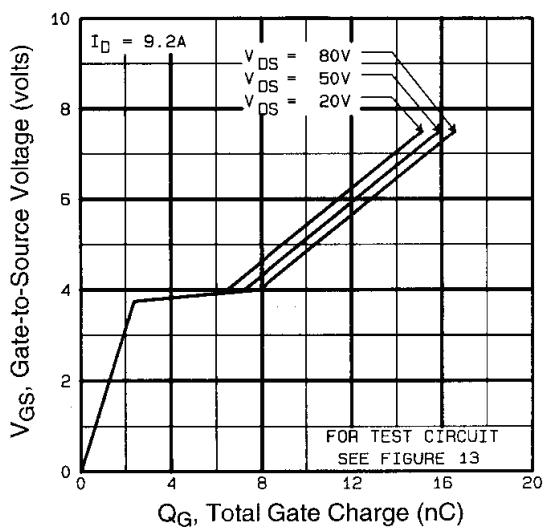


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

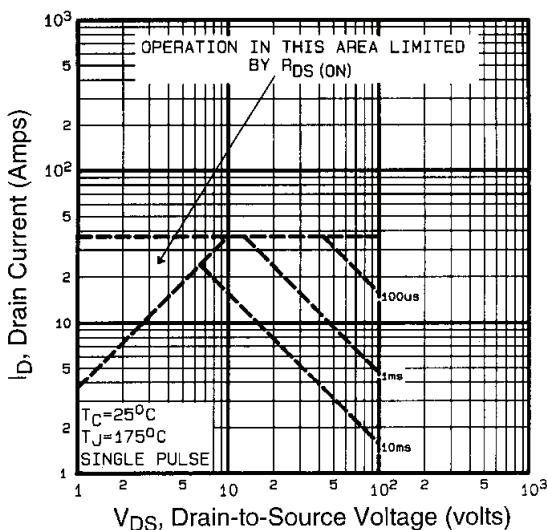


Fig. 8 - Maximum Safe Operating Area

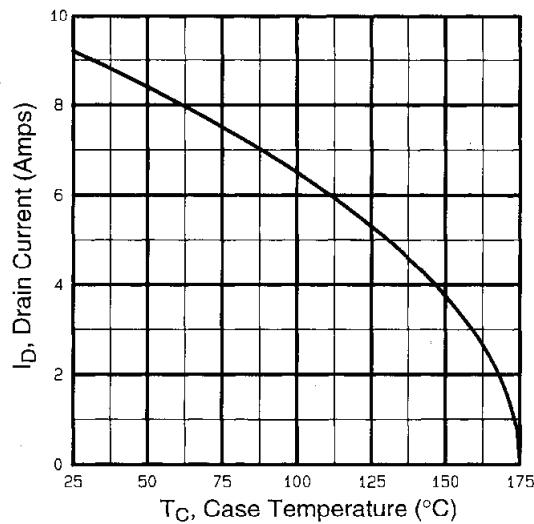


Fig. 9 - Maximum Drain Current vs. Case Temperature

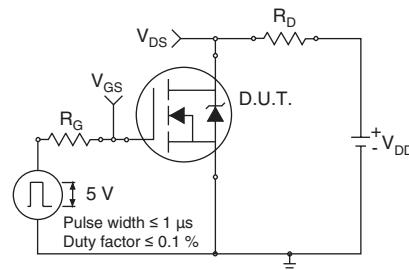


Fig. 10a - Switching Time Test Circuit

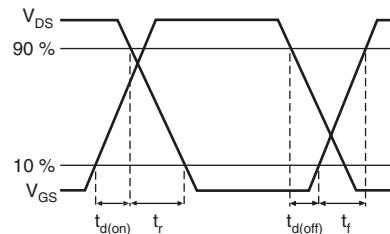


Fig. 10b - Switching Time Waveforms

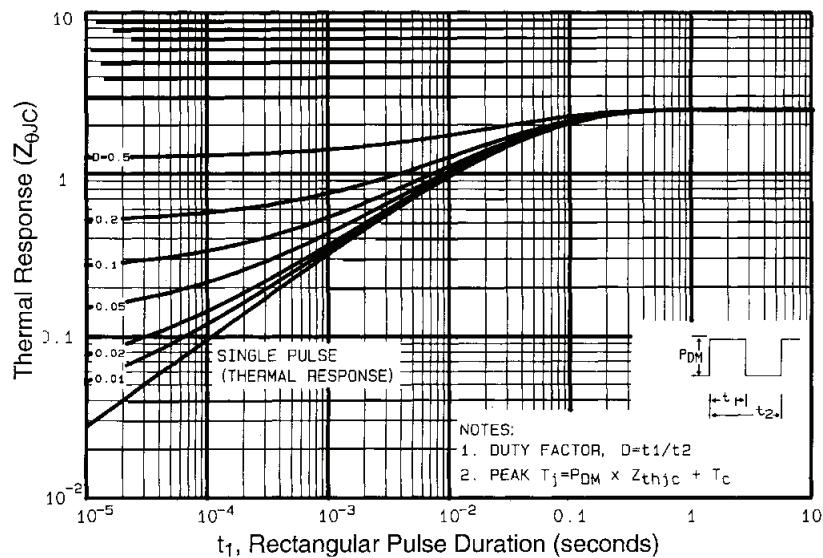


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

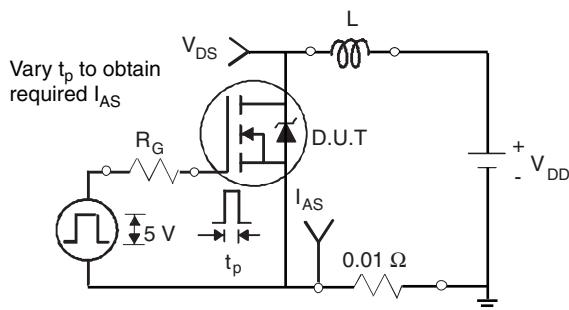


Fig. 12a - Unclamped Inductive Test Circuit

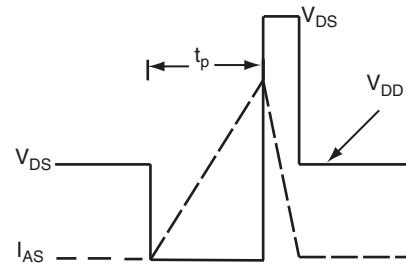


Fig. 12b - Unclamped Inductive Waveforms

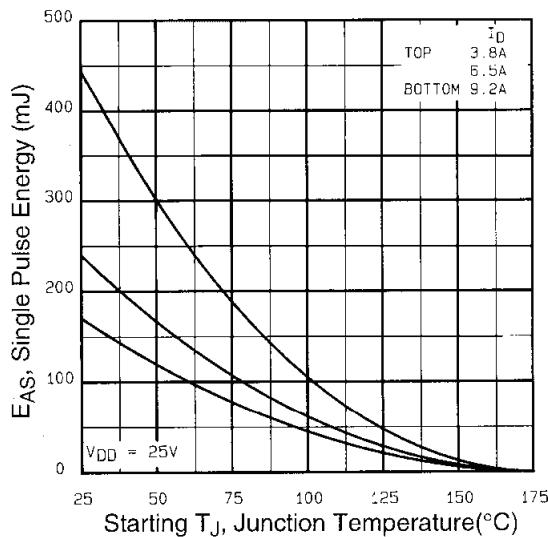


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

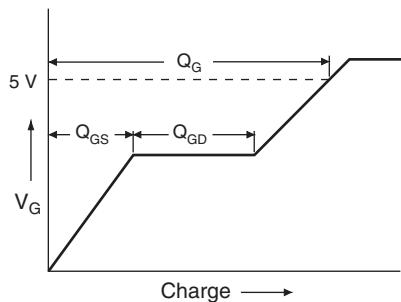


Fig. 13a - Basic Gate Charge Waveform

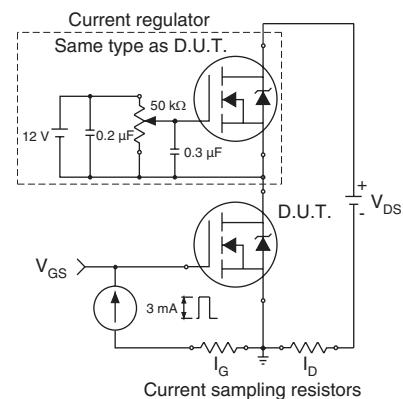
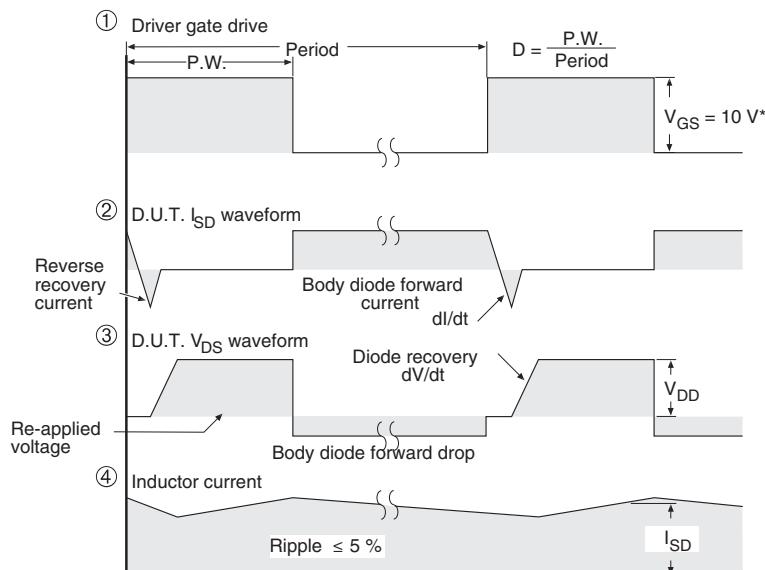
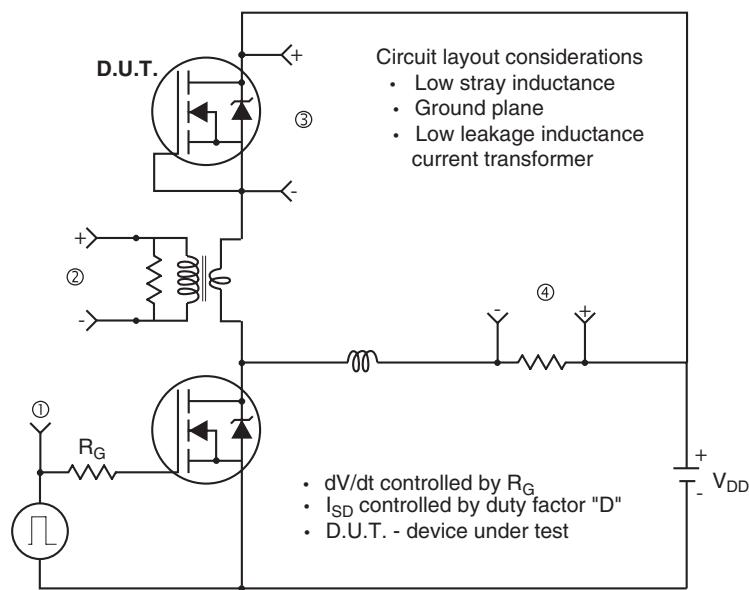


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level and 3 V drive devices

Fig. 14 - For N-Channel

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